











CD74HC4051-EP

SCLS464A - SEPTEMBER 2002-REVISED JANUARY 2015

CD74HC4051-EP Analog Multiplexer and Demultiplexer

Features

- Controlled Baseline
 - One Assembly and Test Site, One Fabrication
- Extended Temperature Performance of -55°C to
- **Enhanced Diminishing Manufacturing Sources** (DMS) Support
- **Enhanced Product Change Notification**
- Qualification Pedigree⁽¹⁾
- Wide Analog Input Voltage Range of ±5 V Max
- Low ON-Resistance
 - 70 Ω Typical (V_{CC} V_{EE} = 4.5 V)
 - 40 Ω Typical ($V_{CC} V_{EE} = 9 \text{ V}$)
- Low Crosstalk Between Switches
- Fast Switching and Propagation Speeds
- Break-Before-Make Switching
- Operation Control Voltage = 2 V to 6 V
- Switch Voltage = 0 V to 10 V
- High Noise Immunity $N_{IL} = 30\%$, $N_{IH} = 30\%$ of V_{CC} , $V_{CC} = 5 V^{(1)}$

2 Applications

Supports Defense and Aerospace Applications

(1) Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

3 Description

The CD74HC4051-EP is a digitally controlled analog switch that uses silicon gate CMOS technology to achieve operating speeds similar to LSTTL, with the low power consumption of standard CMOS integrated circuits.

This analog multiplexer and demultiplexer controls analog voltages that may vary across the voltage supply range (that is, V_{CC} to V_{EE}). These bidirectional switches allow the use of any analog input as an output and vice versa. The switches have low ONresistance and low OFF leakages. In addition, the device has an enable control (E) that, when high, disables all switches to their OFF state.

Device Information(1)

PART NUMBER	PACKAGE	BODY SIZE (NOM)
CD74HC4051-EP	SOIC (16)	4.00 mm × 10.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Functional Block Diagram

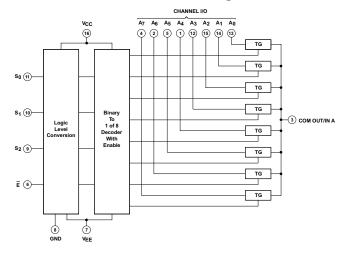




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4 Revision History

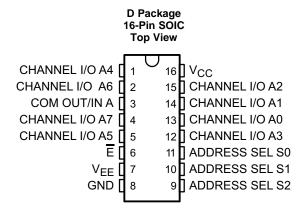
Changes from Original (September 2002) to Revision A

Page

Added ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and



5 Pin Configuration And Functions



Pin Functions

PIN					
NAME	NO.	I/O	DESCRIPTION		
A4	1	I/O	Channel 4 input / output		
A6	2	I/O	Channel 6 Input / output		
Α	3	I/O	COM OUT/ IN		
A7	4	I/O	Channel 7 Input / Output		
A5	5	I/O	Channel 5 Input / Output		
Ebar	6	I	Enable input		
VEE	7	I	Power input level for incoming Channel		
GND	8	I	Power GND		
VCC	9	I	Power input level for outgoing Channel		
A2	10	I/O	Channel 2 Input / Output		
A1	11	I/O	Channel 1 Input / Output		
A0	12	I/O	Channel 0 Input / Output		
A3	13	I/O	Channel 3 Input / Output		
S0	14	1	Address Select Input 0		
S1	15	I	Address Select Input 1		
S2	15	1	Address Select Input 2		

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6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

		MIN	MAX	UNIT
V _{CC} - V _{EE} ⁽²⁾		-0.5	10.5	
V _{CC}	Supply voltage	-0.5	7	V
V _{EE}		0.5	- 7	
I _{IK}	Input clamp current ($V_I < -0.5 \text{ V or } V_I > V_{CC} + 0.5 \text{ V}$)	-20	20	mA
I _{OK}	Output clamp current ($V_O < V_{EE} - 0.5 \text{ V or } V_O > V_{CC} + 0.5 \text{ V}$)	-20	20	mA
	Switch current ($V_I > V_{EE} - 0.5 \text{ V}$ or $V_I < V_{CC} + 0.5 \text{ V}$)	-25	25	mA
	Continuous current through V _{CC} or GND	-50	50	mA
I _{EE}	V _{EE} current	0	20	mA
θ_{JA}	Package thermal impedance ⁽³⁾		73	°C/W
T _J	Maximum junction temperature		150	°C
T _{stg}	Storage temperature	-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±2000	
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	±500	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage (2)		2 6		6	V
	Supply voltage, V _{CC} – V _{EE}	(see Figure 4)	2 10		10	V
V_{EE}	Supply voltage, (see (2) an	d Figure 5)	0 –6		-6	V
		VCC = 2 V	1.5			
V_{IH}	High-level input voltage	VCC = 4.5 V	3.15			V
		VCC = 6 V	4.2			
		VCC = 2 V			0.5	
V_{IL}	Low-level input voltage	VCC = 4.5 V			1.35	V
		VCC = 6 V			1.8	
VI	Input control voltage		0		V_{CC}	V
V _{IS}	Analog switch I/O voltage		V _{EE}		V_{CC}	V
		VCC = 2 V	0		1000	
t _t	Input transition (rise and fall) time	VCC = 4.5 V	0		500	ns
	ian, anio	VCC = 6 V	0		400	

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, SCBA004.

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⁽²⁾ All voltages referenced to GND unless otherwise specified.

⁽³⁾ The package thermal impedance is calculated in accordance with JESD 51-7.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

⁽²⁾ In certain applications, the external load resistor current may include both V_{CC} and signal-line components. To avoid drawing V_{CC} current when switch current flows into the transmission gate inputs, the voltage drop across the bidirectional switch must not exceed 0.6 V (calculated from r_{on} values shown in Electrical Characteristics table). No V_{CC} current flows through R_L if the switch current flows into the COM OUT/IN A terminal.



Recommended Operating Conditions⁽¹⁾ (continued)

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
T_A	Operating free-air temperature	- 55		125	°C
C_{pd}	Power dissipation capacitance (3)		50		рF

f_I = input frequency

C_L = output load capacitance

C_S = switch capacitance

V_{CC} = supply voltage

6.4 Thermal Information

		CD74HC4051-EP	
	THERMAL METRIC ⁽¹⁾	D (SOIC)	UNIT
		16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	81.7	
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	43.1	
$R_{\theta JB}$	Junction-to-board thermal resistance	39.2	°C/W
ΨЈТ	Junction-to-top characterization parameter	10.7	
ΨЈВ	Junction-to-board characterization parameter	38.9	

⁽¹⁾ For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

6.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V	V	T,	(= 25°C		T _A = -5	5°C to 12	25°C	UNIT			
PARAMETER	TEST CC	V _{EE}	V _{cc}	MIN	TYP	MAX	MIN	TYP	MAX	UNIT				
			0 V	4.5 V		70	160			240				
		V _{IS} = V _{CC} or V _{EE}	0 V	6 V		60	140			210				
_	$I_O = 1 \text{ mA}, V_I = V_{IH} \text{ or } V_{II}$		-4.5 V	4.5 V		40	120			180	Ω			
r _{on}	See Figure 1		0 V	4.5 V		90	180			270	12			
		$V_{IS} = V_{CC}$ to V_{EE}	0 V	6 V		80	160			240				
			-4.5 V	4.5 V		45	130			195				
		•	0 V	4.5 V		10								
Δr_{on}	Between any two channels	hannels		tween any two channels	Between any two channels	0 V	6 V		8.5					Ω
			-4.5 V	4.5 V		5								
	For switch OFF:		0 V	6 V			±0.2			±2				
I _{IZ}			–5 V	5 V			±0.4			±4	μА			
I _{IL}	V _I = V _{CC} or GND		0 V	6 V			±0.1			±1	μΑ			
	$\begin{array}{c} \text{When V}_{\text{IS}} = \text{V}_{\text{EE}}, \text{V}_{\text{OS}} = \\ \text{V}_{\text{CC}} \end{array}$		0 V	6 V			8			160				
I _{CC}	$I_O = 0$, $V_I = V_{CC}$ or GND	When $V_{IS} = V_{CC}$, $V_{OS} = V_{EE}$	–5 V	5 V			16			320	μA			

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6.6 Analog Channel Characteristics

 $T_A = 25^{\circ}C$

	PARAMETER	PARAMETER TEST CONDITIONS		V _{cc}	MIN TYP	MAX	UNIT
Cı	Switch input capacitance				5		pF
C_{COM}	Common output capacitance				25		pF
ı	Minimum switch frequency response	See Figure 6, Figure 2, and (1)(2)	-2.25 V	2.25 V	145		MHz
Imax	at –3 dB	See Figure 6, Figure 2, and V //	-4.5 V	4.5 V	180		IVITZ
	Cine ways distortion	Con Figure 7	–2.25 V	2.25 V	0.03%		
	Sine-wave distortion	See Figure 7	-4.5 V	4.5 V	0.018%		
	Switch OFF signal foodthrough	See Figure 8, Figure 3 and ⁽²⁾⁽³⁾	–2.25 V	2.25 V	-73		dB
	Switch OFF signal feedthrough	See Figure 6, Figure 3 and	-4.5 V	4.5 V	-7 5		uБ

- (1) Adjust input voltage to obtain 0 dBm at V_{OS} for f_{IN} = 1 MHz. (2) V_{IS} is centered at $(V_{CC} V_{EE})/2$. (3) Adjust input for 0 dBm

6.7 Switching Characteristics

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 9)

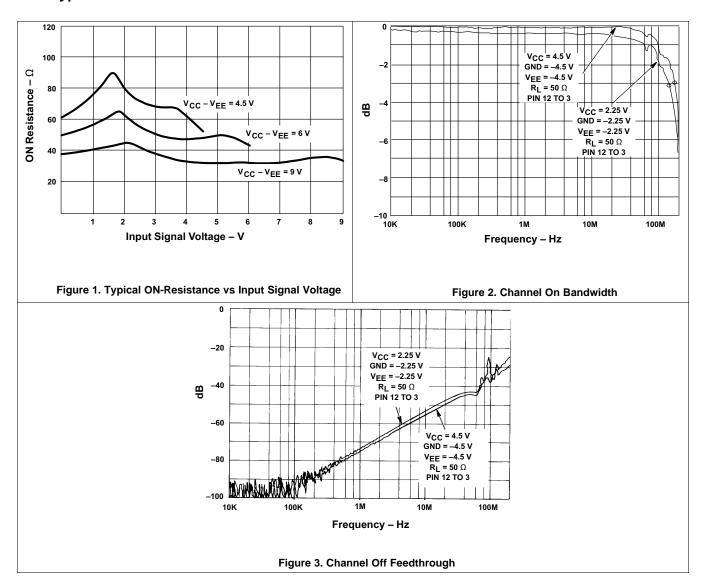
DADAMETER	FROM	то	LOAD	.,	.,	1	Γ _A = 25°C		T _A = −5	5°C TO 125°	С	LINUT	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	V _{EE}	V _{EE} V _{CC}	MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
			C _L = 15 pF		5 V			4					
					2 V			60			90		
t_{pd}	IN	OUT	C 50 mF	0 V	4.5 V			12			18	ns	
	IIN	001	$C_L = 50 pF$		6 V			10			15		
				-4.5 V	4.5 V			8			12		
			C _L = 15 pF		5 V			19					
						2 V			225			340	
	ADDRESS SEL or	OUT	C 50 mF	0 V	4.5 V			45			68	ns	
t _{en}	Ē	001	$C_L = 50 pF$		6 V			38			57		
				-4.5 V	4.5 V			32			48		
			C _L = 15 pF		5 V			19					
					2 V			225			340		
t _{dis}	ADDRESS SEL or	OUT	C _L = 50 pF	0 V	4.5 V			45			68	ns	
	_		C _L = 50 pF		6 V			38			57		
				-4.5 V	4.5 V			32			48		
Cı	Control		C _L = 50 pF					10			10	pF	

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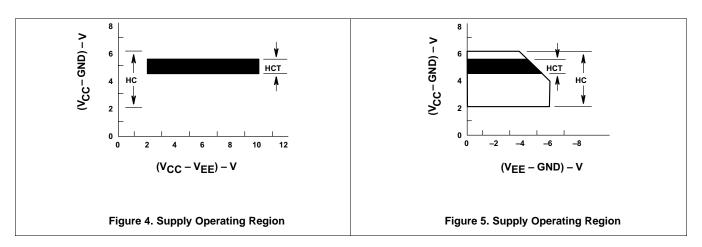
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6.8 Typical Characteristics



6.8.1 Recommended Operating Area as a Function of Supply Voltages



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7 Parameter Measurement Information

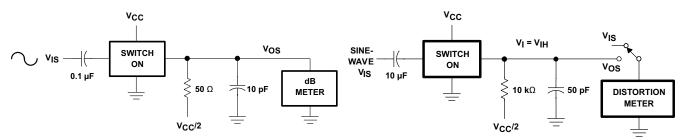


Figure 6. Frequency-Response Test Circuit

Figure 7. Sine-Wave Distortion Test Circuit

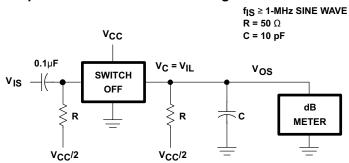
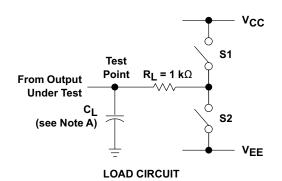


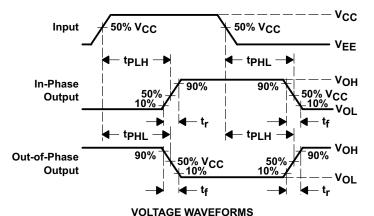
Figure 8. Switch OFF Signal Feedthrough Test Circuit

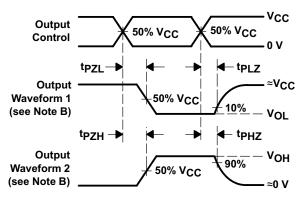


Parameter Measurement Information (continued)



PARA	METER	S1	S2
	^t PZH	Open	Closed
t _{en}	tPZL	Closed	Open
tdis	tPHZ	Open	Closed
dis	tPLZ	Closed	Open
tpd		Open	Open





VOLTAGE WAVEFORMS
OUTPUT ENABLE AND DISABLE TIMES

PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_Γ = 6 ns, t_f = 6 ns.
- D. For clock inputs, $f_{\mbox{max}}$ is measured with the input duty cycle at 50%.
- E. The outputs are measured one at a time with one input transition per measurement.
- F. tpLz and tpHz are the same as tdis.
- G. tpzL and tpzH are the same as ten.
- H. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 9. Load Circuit and Voltage Waveforms

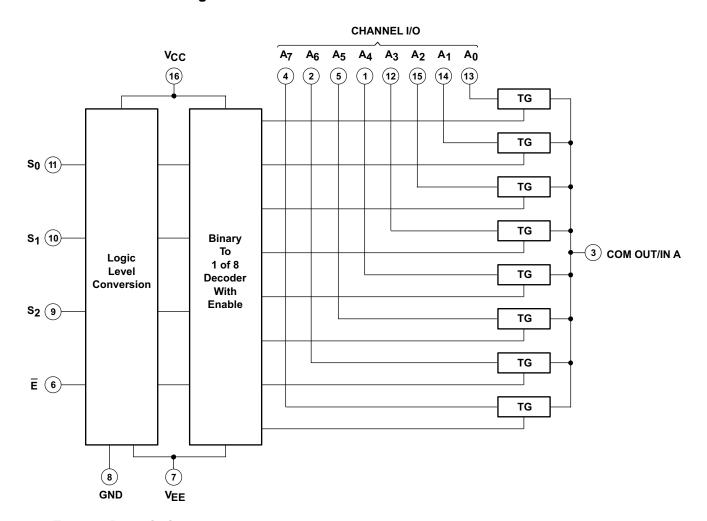


8 Detailed Description

8.1 Overview

The CD74HC4051-EP is a digitally controlled analog switch that uses silicon gate CMOS technology to achieve operating speeds similar to LSTTL, with the low-power consumption of standard CMOS integrated circuits.

8.2 Functional Block Diagram



8.3 Feature Description

This analog multiplexer and demultiplexer controls analog voltages that may vary across the voltage supply range (that is, VCC to VEE). These bidirectional switches allow the use of any analog input as an output and vice versa. The switches have low ON-resistance and low OFF leakages. In addition, the device has an enable control (E) that, when high, disables all switches to their OFF state.



8.4 Device Functional Modes

Table 1. Function Table

INPUTS				ON CHANNEL
E	S2	S1	S0	(S)
L	L	L	L	A0
L	L	L	Н	A1
L	L	Н	L	A2
L	L	Н	Н	A3
L	Н	L	L	A4
L	Н	L	Н	A5
L	Н	Н	L	A6
L	Н	Н	Н	A7
Н	X	X	X	None

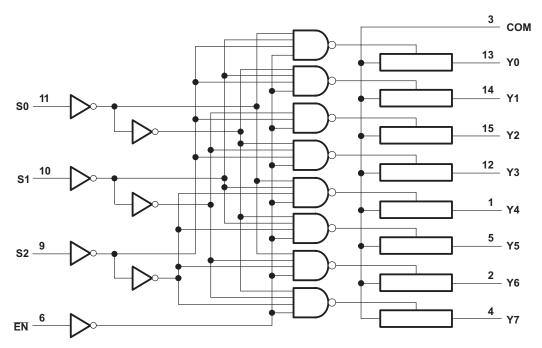


Figure 10. Logic Diagram (Positive Logic)



9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

9.1.1 TTL-to-HC Interface

TTL output voltages and HC input voltages are incompatible, especially between the TTL high-level output voltage (V_{OH}) and the HC high-level input voltage (V_{IH}). This problem can be solved in two different ways. The first solution is to provide pullup resistors at the TTL outputs to ensure an adequate high-level TTL output voltage. A alternative method requires the use of level shifters.

9.2 Typical Application

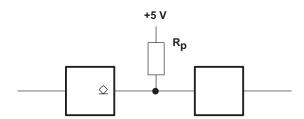


Figure 11. Typical Application Schematic TTL-to-HC Interface Using Open-Collector Output.

9.2.1 Design Requirements

Interfacing TTL open-collector outputs to HC-CMOS inputs requires design of pullup circuit balanced with drive capability to achieve timing and VOL-HC input specifications. Similar technique can be applied when using open-drain outputs.

9.2.2 Detailed Design Procedure

Using pullup resistors to accommodate TTL output signals to interface with HC input circuits (see Figure 11), the design engineer must choose the resistance that is appropriate for the application. The minimum value of the resistor is determined by the maximum current I_{OL} that a TTL circuit can supply at the low-level output (V_{OL}).

$$R_{p}\,min = \frac{V_{CC}\,max - V_{OL}min}{I_{OL} + n \times I_{IL}}$$

where

n is the number of HC inputs to be driven

I_{IL}, having a value of only a few nanoamperes, is negligible in all calculations.

In the case of a SN74ALS03, Equation 2 defines R_pmin:

$$R_{p} \min = \frac{5.5 V - 0.4 V}{8 \text{mA}} = 640 \Omega \tag{2}$$

To calculate the upper limit of this resistor, a sufficient V_{IH} high level must be ensured.

$$R_{p} \max = \frac{V_{CC} - V_{IH} \min}{n \times I_{IH}}$$
(3)

In this situation, the input current of HC devices is negligible and very high values also are obtained.



Typical Application (continued)

When calculating the maximum allowable resistance, it is important to ensure that the maximum allowable rise time ($t_r = 500 \text{ ns}$) at the HC input is not exceeded. Equation 4 then applies:

$$V_{IH} = V_{CC}(1 - e^{\frac{-t}{R_p \times C}})$$

where

C is the total load capacitance in the circuit

(4)

C is composed of the output capacitance of the driving gate (approximately 10 pF), the total input capacitances of gates to be driven (approximately 5 pF each), and the line capacitance (approximately 1 pF/cm). The actual value is calculated by solving the equation for R_p :

$$R_{p} = \frac{-t}{C \times \ln(1 - \frac{3.5V}{5V})} \tag{5}$$

Assuming the total capacitance, C, is 30 pF, the maximum resistor is:

$$R_{p} = \frac{-500 \text{ns}}{30 \text{pF} \times \ln(1 - \frac{3.5 \text{V}}{5 \text{V}})} = 14 \text{k}\Omega$$
(6)

Faster rise times result in lower impedance and more power consumption. The previous calculation is based on the assumption that the driving gate has an open collector. Conditions become more satisfactory, however, when a gate with totem-pole output (that is, SN74ALS00) is used. In that case, the gate output provides the voltage to be brought up to the value $V_{OH} = 2.7 \text{ V}$ in less than 10 ns (the rise time of the TTL signal). The pullup resistor only has to pull the level to 3.5 V within the desired time. According to the previous formula, and with a required rise time of $t_r = 50 \text{ ns}$, the resistor is defined by Equation 7:

$$R_{p} max = \frac{-50 ns - 10 ns}{30 pF \times ln(1 - \frac{3.5 V - 2.7 V}{5 V - 2.7 V})} = 3.12 k\Omega$$
(7)

The upper limiting value of the resistor is primarily dictated by the rise time required. The larger the resistance, the longer the rise times and propagation delay times. Reducing the resistance increases speed and power dissipation.

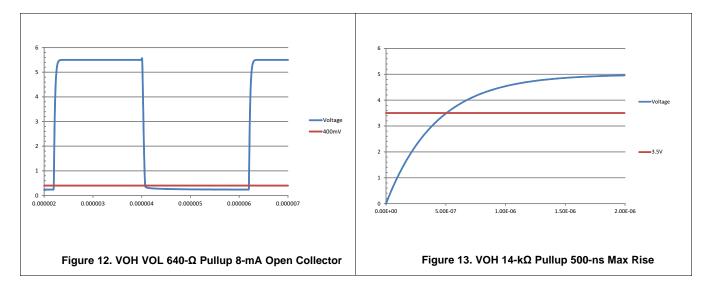
The other method of accommodating TTL signals to HC circuits is accomplished with special level shifters. This solution is not recommended because the level shifter itself has no inherent logic functions and increases component and space requirements.

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Typical Application (continued)

9.2.3 Application Curves





10 Power Supply Recommendations

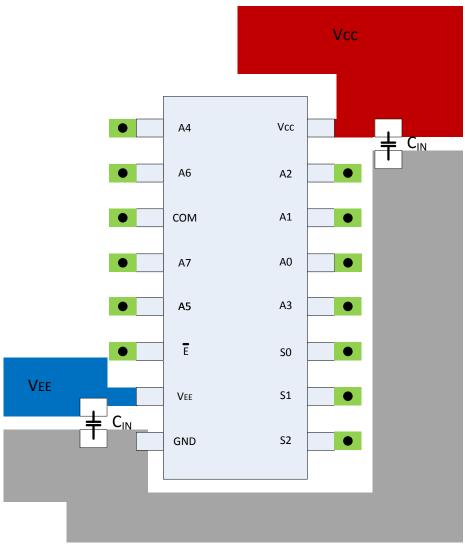
The threshold voltage of a CMOS circuit is determined by the geometry of the input transistors. These transistors are designed to sink the same input current at the required threshold voltage. The resulting voltage at the output is equivalent to 50% of the supply voltage V_{CC} . For an HC circuit, the channel width of the P-channel transistor of the input is approximately twice the value of an N-channel transistor. The purpose is to make both transistors have the same current characteristics, thus making the threshold voltage of their input at about 50% of the supply voltage V_{CC} .

11 Layout

11.1 Layout Guidelines

Analog channels inputs and outputs should be routed to optimize system requirements. VCC and VEE should have local decoupling capacitance placed close to device. Typical Cin values are 100 pF and 0.01 uF per supply pin.

11.2 Layout Example



VIAS USED TO CONNECT PINS FOR APPLICATION SPECIFIC CONNECTIONS

Figure 14. Layout Example

Product Folder Links: CD74HC4051-EP

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12 Device And Documentation Support

12.1 Trademarks

All trademarks are the property of their respective owners.

12.2 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.3 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

10-Nov-2025 www.ti.com

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
CD74HC4051MM96EP	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4051MEP
CD74HC4051MM96EP.A	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4051MEP
V62/03606-01XE	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4051MEP

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF CD74HC4051-EP:

Catalog: CD74HC4051

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

www.ti.com 10-Nov-2025

• Automotive : CD74HC4051-Q1

Military: CD54HC4051

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC4051MM96EP	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

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*All dimensions are nominal

	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
ı	CD74HC4051MM96EP	SOIC	D	16	2500	353.0	353.0	32.0	

D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



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